

Notice of References Cited	Application/Control No. 10/601,548	Applicant(s)/Patent Under Reexamination CHANG ET AL.	
	Examiner Patrick J. Connolly	Art Unit 2877	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Akiba M. et al "En-face optical coherence imaging for three-dimensional microscopy" Proceedings of the SPIE - The International Society For Optical Engineering Spie-Int. vol 4621, May 2002, pages 8-15
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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